# December 1999 ADVANCE INFORMATION

# **FDZ5047N**

# 30V N-Channel Logic Level PowerTrench® BGA MOSFET

# **General Description**

Combining Fairchild's 30V PowerTrench process with state of the art BGA packaging, the FDZ5047N minimizes both PCB space and  $R_{\rm DS(ON)}.$  This BGA MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, high current handling capability, ultra-low profile packaging, low gate charge, and low  $R_{\rm DS(ON)}.$ 

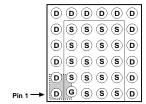
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable  $R_{\text{DS(ON)}}$  specifications resulting in DC/DC power supply designs with higher overall efficiency.

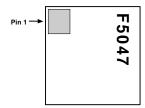
# **Applications**

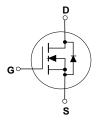
- DC/DC Converters
- · Solenoid drive

# **Features**

- 22 A, 30 V.  $R_{DS(ON)} = 0.0035 \; \Omega \; @ \; V_{GS} = 10 \; V$   $R_{DS(ON)} = 0.0050 \; \Omega \; @ \; V_{GS} = 4.5 \; V.$
- Occupies only 27.5 mm<sup>2</sup> of PCB area.
   1/5 of the area of a TO-220 package.
- Ultra-thin package: less than 0.80 mm height when mounted to PCB.
- Outstanding thermal transfer characteristics.
- $\bullet~$  Ultra-low gate charge x  $R_{\text{DS(ON)}}~$  product.
- 175°C maximum junction temperature rating.







**Bottom** 

Top

# Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain-Source Voltage	30	V
V <sub>GSS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub>	Drain Current - Continuous (Note 1a)	22	Α
	- Pulsed	75	1
P <sub>D</sub>	Total Power Dissipation @ T <sub>A</sub> = 25°C	3.3	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-65 to +175	°C

# **Thermal Characteristics**

$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	45	°C/W

# **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape width	Quantity
F5047	FDZ5047N	TBD	TBD	TBD

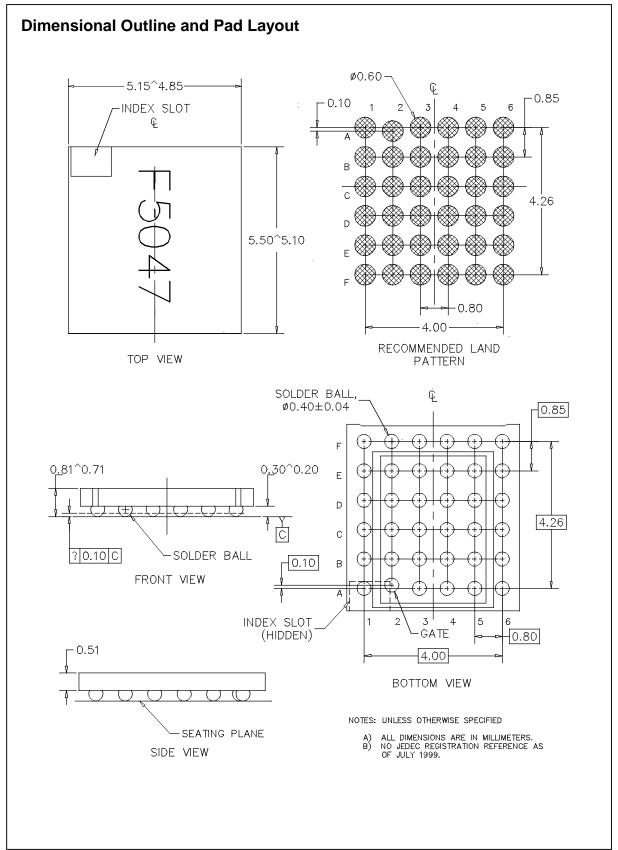
Electri	cal Characteristics	T <sub>A</sub> = 25°C unless otherwise noted				
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		•	•		•
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		22		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I <sub>GSSF</sub>	Gate-Body Forward Leakage	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Reverse Leakage	$V_{GS} = -20 \text{ V}$ $V_{DS} = 0 \text{ V}$			100	nA
On Char	acteristics (Note 2)				ı	u
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	1.5	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_{,l}}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		<b>-</b> 5		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 22 \text{ A} $ $V_{GS} = 4.5 \text{ V}, \qquad I_D = 18 \text{ A}$		3.0 4.2	3.5 5.0	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	50			Α
Dynamic	Characteristics	•	•		•	
Ciss	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		5400		pF
Coss	Output Capacitance	f = 1.0 MHz		1170		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			530		pF
Switchir	ng Characteristics (Note 2)				ı	u
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		50	70	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 5 V$		16		nC
Q <sub>gd</sub>	Gate-Drain Charge			16		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	Diode Forward Current (Note 1a)			3	Α
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 22 \text{ A}$ (Note 2)		0.95	1.2	V

Notes:

1. R<sub>0JA</sub> is a function of the junction-to-case (R<sub>0JC</sub>), case-to-ambient (R<sub>0CA</sub>) and the PC Board (R<sub>0BA</sub>) thermal resistance. For the purpose of determining R<sub>0JC</sub> the case thermal reference is defined as the top surface of the package. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> and R<sub>0BA</sub> are determined by the user's

<sup>(</sup>a).  $\rm R_{\theta JA} = 45^{\circ} C/W$  (steady-state) when mounted on 1 in  $^{2}$  of 2 oz. copper.

<sup>2.</sup> Pulse Test: Pulse Width <  $300\mu s$ , Duty Cycle < 2.0%



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